

N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS}	40	V		
R _{DS(on)} V _{GS} = 10 V	2	mΩ		
I _D	180	Α		
Configuration	Single			

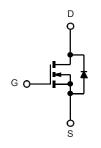
FEATURES

- Trench Power MOSFET
- 100 % R_g and UIS Tested



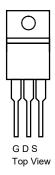
APPLICATIONS

- · Synchronous Rectification
- · Power Supplies



N-Channel MOSFET

TO-220AB



Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	40		
Gate-Source Voltage		V_{GS}	± 20	V	
Continuous Drain Current (T _J = 175 °C)	T _C = 25 °C		180 ^{a, c}	. А	
	T _C = 70 °C		150°		
	T _A = 25 °C	l _D	29 ^b		
	T _A = 70 °C		23 ^b		
Pulsed Drain Current		I _{DM}	350		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	80		
Single Pulse Avalanche Energy	L = 0.11111	E _{AS}	320	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	110 ^{a, c}	А	
Continuous Source-Diam Diode Current	T _A = 25 °C	'S	2.6 ^b		
Maximum Power Dissipation	T _C = 25 °C		312ª		
	T _C = 70 °C	P _D	200	w	
	T _A = 25 °C	' D	3.13 ^b		
	T _A = 70 °C		2.0 ^b		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^b	Steady State	R_{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.33	0.4	C/VV	

Notes:

- a. Based on $T_C = 25\,^{\circ}C$.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. Calculated based on maximum junction temperature. Package limitation current is 110 \mbox{A} .



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	40			V	
V _{DS} Temperature Coefficient	Δ V _{DS} /T _J	I _D = 250 μA		41		mV/°C	
V _{GS(th)} Temperature Coefficient	△ V _{GS(th)} /T _J	1 _D = 230 μΑ		- 8		mv/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Cata Valta na Duain Commant	1	V _{DS} = 40 V, V _{GS} = 0 V	1		1		
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	10 µA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α	
Davis Occurs On Otata Basistanas	P	$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$		2		mO	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 20 \text{ A}$		15		mΩ	
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 15 \text{ V}, I_D = 30 \text{ A}$		180		S	
Dynamic ^b							
Input Capacitance	C _{iss}			9000		pF	
Output Capacitance	C _{oss}	V_{DS} = 20 V, V_{GS} = 0 V, f = 1 MHz		650			
Reverse Transfer Capacitance	C _{rss}			450			
Total Gate Charge	Qg			120		nC	
Gate-Source Charge	Q _{gs}	$V_{DS} = 20 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 20 \text{ A}$		30			
Gate-Drain Charge	Q _{gd}			16			
Gate Resistance	R _g	f = 1 MHz		0.85	1.3	Ω	
Turn-On Delay Time	t _{d(on)}			20	30		
Rise Time	t _r	V_{DD} = 20 V, R_L = 1.0 Ω		11	17		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 20 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		77	115		
Fall Time	t _f			10	15	no	
Turn-On Delay Time	t _{d(on)}			102	155	ns	
Rise Time	t _r	V_{DD} = 20 V, R_L = 1.0 Ω		62	95		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 20 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		180	270		
Fall Time	t _f			60	90		
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	Is	T _C = 25 °C			110	Α	
Pulse Diode Forward Current ^a	I _{SM}				200		
Body Diode Voltage	V _{SD}	I _S = 20 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			50	75	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _E = 20 A, di/dt = 100 A/μs, T _{.I} = 25 °C		70	105	nC	
Reverse Recovery Fall Time	t _a	1 _F = 20 A, αι/αι = 100 Α/μο, 1 _J = 20 C		30		no	
Reverse Recovery Rise Time	t _b			20		ns	

Notes:

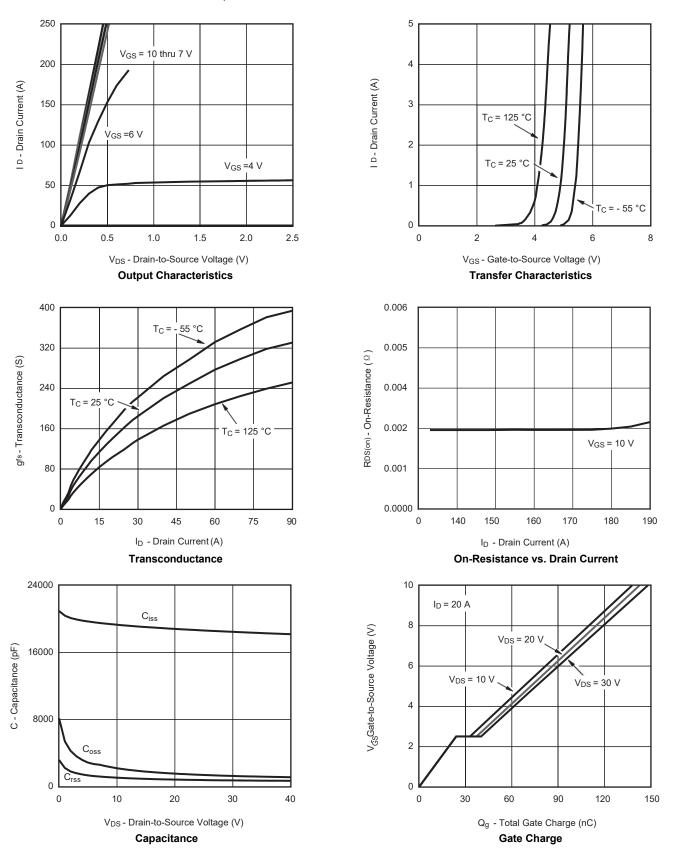
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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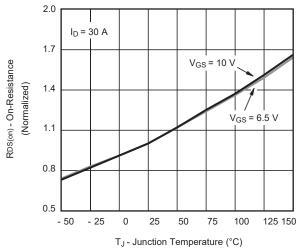


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

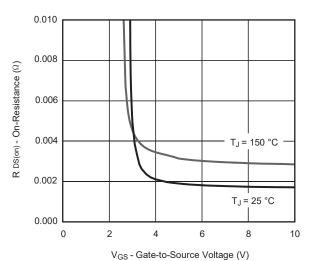




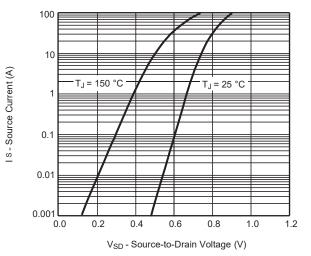
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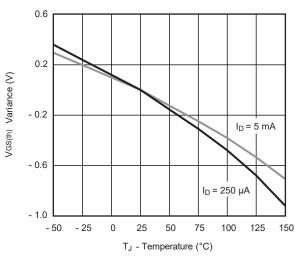
On-Resistance vs. Junction Temperature



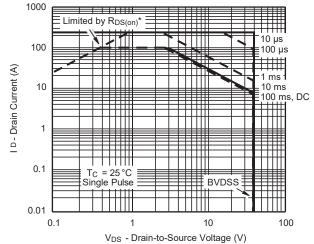
On-Resistance vs. Gate-to-Source Voltage



Forward Diode Voltage vs. Temperature



Threshold Voltage

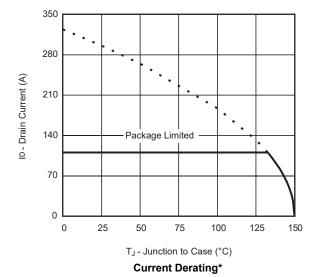


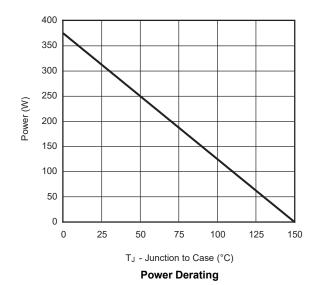
* V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

Safe Operating Area, Junction-to-Ambient

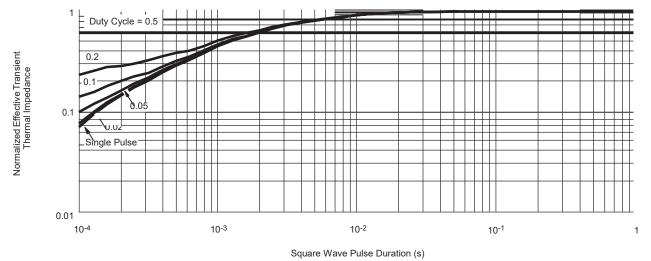


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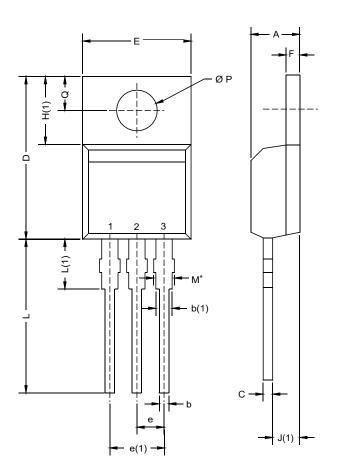
* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case



TO-220AB



	MILLIM	ETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

Notes

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM

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